

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/731,143 | Applicant(s)/Patent Under Reexamination OKURA ET AL. | |
| | Examiner Anh T. Mai | Art Unit 2832 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-5,449,861 | 09-1995 | Fujino et al. | 174/113A |
| | B | US-6,867,374 | 03-2005 | Ishigaki et al. | 174/110A |
| | C | US-6,313,409 | 11-2001 | Bales et al. | 174/128.1 |
| | D | US-6,555,753 | 04-2003 | Rutledge et al. | 174/128.1 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP 06181007 A | 06-1994 | Japan | TANAKA et al. | H01B 07/00 |
| | O | JP 2001167641 A | 06-2001 | Japan | NAKAO et al. | H01B 07/02 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.